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# Understanding <u>Embedded - FPGAs (Field Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	13824
Total RAM Bits	110592
Number of I/O	215
Number of Gates	600000
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	281-TFBGA, CSBGA
Supplier Device Package	281-CSP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/agl600v5-cs281i

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

# 1 – IGLOO Device Family Overview

## **General Description**

The IGLOO family of flash FPGAs, based on a 130-nm flash process, offers the lowest power FPGA, a single-chip solution, small footprint packages, reprogrammability, and an abundance of advanced features.

The Flash\*Freeze technology used in IGLOO devices enables entering and exiting an ultra-low power mode that consumes as little as 5 µW while retaining SRAM and register data. Flash\*Freeze technology simplifies power management through I/O and clock management with rapid recovery to operation mode.

The Low Power Active capability (static idle) allows for ultra-low power consumption (from 12  $\mu$ W) while the IGLOO device is completely functional in the system. This allows the IGLOO device to control system power management based on external inputs (e.g., scanning for keyboard stimulus) while consuming minimal power.

Nonvolatile flash technology gives IGLOO devices the advantage of being a secure, low power, singlechip solution that is Instant On. IGLOO is reprogrammable and offers time-to-market benefits at an ASIClevel unit cost.

These features enable designers to create high-density systems using existing ASIC or FPGA design flows and tools.

IGLOO devices offer 1 kbit of on-chip, reprogrammable, nonvolatile FlashROM storage as well as clock conditioning circuitry based on an integrated phase-locked loop (PLL). The AGL015 and AGL030 devices have no PLL or RAM support. IGLOO devices have up to 1 million system gates, supported with up to 144 kbits of true dual-port SRAM and up to 300 user I/Os.

M1 IGLOO devices support the high-performance, 32-bit Cortex-M1 processor developed by ARM for implementation in FPGAs. Cortex-M1 is a soft processor that is fully implemented in the FPGA fabric. It has a three-stage pipeline that offers a good balance between low power consumption and speed when implemented in an M1 IGLOO device. The processor runs the ARMv6-M instruction set, has a configurable nested interrupt controller, and can be implemented with or without the debug block. Cortex-M1 is available for free from Microsemi for use in M1 IGLOO FPGAs.

The ARM-enabled devices have ordering numbers that begin with M1AGL and do not support AES decryption.

## Flash\*Freeze Technology

The IGLOO device offers unique Flash\*Freeze technology, allowing the device to enter and exit ultra-low power Flash\*Freeze mode. IGLOO devices do not need additional components to turn off I/Os or clocks while retaining the design information, SRAM content, and registers. Flash\*Freeze technology is combined with in-system programmability, which enables users to quickly and easily upgrade and update their designs in the final stages of manufacturing or in the field. The ability of IGLOO V2 devices to support a wide range of core voltage (1.2 V to 1.5 V) allows further reduction in power consumption, thus achieving the lowest total system power.

When the IGLOO device enters Flash\*Freeze mode, the device automatically shuts off the clocks and inputs to the FPGA core; when the device exits Flash\*Freeze mode, all activity resumes and data is retained.

The availability of low power modes, combined with reprogrammability, a single-chip and single-voltage solution, and availability of small-footprint, high pin-count packages, make IGLOO devices the best fit for portable electronics.

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## Flash Advantages

## Low Power

Flash-based IGLOO devices exhibit power characteristics similar to those of an ASIC, making them an ideal choice for power-sensitive applications. IGLOO devices have only a very limited power-on current surge and no high-current transition period, both of which occur on many FPGAs.

IGLOO devices also have low dynamic power consumption to further maximize power savings; power is even further reduced by the use of a 1.2 V core voltage.

Low dynamic power consumption, combined with low static power consumption and Flash\*Freeze technology, gives the IGLOO device the lowest total system power offered by any FPGA.

## Security

Nonvolatile, flash-based IGLOO devices do not require a boot PROM, so there is no vulnerable external bitstream that can be easily copied. IGLOO devices incorporate FlashLock, which provides a unique combination of reprogrammability and design security without external overhead, advantages that only an FPGA with nonvolatile flash programming can offer.

IGLOO devices utilize a 128-bit flash-based lock and a separate AES key to provide the highest level of protection in the FPGA industry for intellectual property and configuration data. In addition, all FlashROM data in IGLOO devices can be encrypted prior to loading, using the industry-leading AES-128 (FIPS192) bit block cipher encryption standard. AES was adopted by the National Institute of Standards and Technology (NIST) in 2000 and replaces the 1977 DES standard. IGLOO devices have a built-in AES decryption engine and a flash-based AES key that make them the most comprehensive programmable logic device security solution available today. IGLOO devices with AES-based security provide a high level of protection for remote field updates over public networks such as the Internet, and are designed to ensure that valuable IP remains out of the hands of system overbuilders, system cloners, and IP thieves.

Security, built into the FPGA fabric, is an inherent component of the IGLOO family. The flash cells are located beneath seven metal layers, and many device design and layout techniques have been used to make invasive attacks extremely difficult. The IGLOO family, with FlashLock and AES security, is unique in being highly resistant to both invasive and noninvasive attacks. Your valuable IP is protected with industry-standard security, making remote ISP possible. An IGLOO device provides the best available security for programmable logic designs.

## Single Chip

Flash-based FPGAs store their configuration information in on-chip flash cells. Once programmed, the configuration data is an inherent part of the FPGA structure, and no external configuration data needs to be loaded at system power-up (unlike SRAM-based FPGAs). Therefore, flash-based IGLOO FPGAs do not require system configuration components such as EEPROMs or microcontrollers to load device configuration data. This reduces bill-of-materials costs and PCB area, and increases security and system reliability.

## Instant On

Flash-based IGLOO devices support Level 0 of the Instant On classification standard. This feature helps in system component initialization, execution of critical tasks before the processor wakes up, setup and configuration of memory blocks, clock generation, and bus activity management. The Instant On feature of flash-based IGLOO devices greatly simplifies total system design and reduces total system cost, often eliminating the need for CPLDs and clock generation PLLs. In addition, glitches and brownouts in system power will not corrupt the IGLOO device's flash configuration, and unlike SRAM-based FPGAs, the device will not have to be reloaded when system power is restored. This enables the reduction or complete removal of the configuration PROM, expensive voltage monitor, brownout detection, and clock generator devices from the PCB design. Flash-based IGLOO devices simplify total system design and reduce cost and design risk while increasing system reliability and improving system initialization time.

IGLOO flash FPGAs allow the user to quickly enter and exit Flash\*Freeze mode. This is done almost instantly (within 1 µs) and the device retains configuration and data in registers and RAM. Unlike SRAM-based FPGAs the device does not need to reload configuration and design state from external memory components; instead it retains all necessary information to resume operation immediately.

## Reduced Cost of Ownership

Advantages to the designer extend beyond low unit cost, performance, and ease of use. Unlike SRAM-based FPGAs, Flash-based IGLOO devices allow all functionality to be Instant On; no external boot PROM is required. On-board security mechanisms prevent access to all the programming information and enable secure remote updates of the FPGA logic. Designers can perform secure remote in-system reprogramming to support future design iterations and

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#### User Nonvolatile FlashROM

IGLOO devices have 1 kbit of on-chip, user-accessible, nonvolatile FlashROM. The FlashROM can be used in diverse system applications:

- · Internet protocol addressing (wireless or fixed)
- · System calibration settings
- · Device serialization and/or inventory control
- Subscription-based business models (for example, set-top boxes)
- · Secure key storage for secure communications algorithms
- Asset management/tracking
- Date stamping
- · Version management

The FlashROM is written using the standard IGLOO IEEE 1532 JTAG programming interface. The core can be individually programmed (erased and written), and on-chip AES decryption can be used selectively to securely load data over public networks (except in the AGL015 and AGL030 devices), as in security keys stored in the FlashROM for a user design.

The FlashROM can be programmed via the JTAG programming interface, and its contents can be read back either through the JTAG programming interface or via direct FPGA core addressing. Note that the FlashROM can only be programmed from the JTAG interface and cannot be programmed from the internal logic array.

The FlashROM is programmed as 8 banks of 128 bits; however, reading is performed on a byte-by-byte basis using a synchronous interface. A 7-bit address from the FPGA core defines which of the 8 banks and which of the 16 bytes within that bank are being read. The three most significant bits (MSBs) of the FlashROM address determine the bank, and the four least significant bits (LSBs) of the FlashROM address define the byte.

The Microsemi development software solutions, Libero<sup>®</sup> System-on-Chip (SoC) and Designer, have extensive support for the FlashROM. One such feature is auto-generation of sequential programming files for applications requiring a unique serial number in each part. Another feature allows the inclusion of static data for system version control. Data for the FlashROM can be generated quickly and easily using Libero SoC and Designer software tools. Comprehensive programming file support is also included to allow for easy programming of large numbers of parts with differing FlashROM contents.

## SRAM and FIFO

IGLOO devices (except the AGL015 and AGL030 devices) have embedded SRAM blocks along their north and south sides. Each variable-aspect-ratio SRAM block is 4,608 bits in size. Available memory configurations are 256x18, 512x9, 1kx4, 2kx2, and 4kx1 bits. The individual blocks have independent read and write ports that can be configured with different bit widths on each port. For example, data can be sent through a 4-bit port and read as a single bitstream. The embedded SRAM blocks can be initialized via the device JTAG port (ROM emulation mode) using the UJTAG macro (except in the AGL015 and AGL030 devices).

In addition, every SRAM block has an embedded FIFO control unit. The control unit allows the SRAM block to be configured as a synchronous FIFO without using additional core VersaTiles. The FIFO width and depth are programmable. The FIFO also features programmable Almost Empty (AEMPTY) and Almost Full (AFULL) flags in addition to the normal Empty and Full flags. The embedded FIFO control unit contains the counters necessary for generation of the read and write address pointers. The embedded SRAM/FIFO blocks can be cascaded to create larger configurations.

#### PLL and CCC

IGLOO devices provide designers with very flexible clock conditioning circuit (CCC) capabilities. Each member of the IGLOO family contains six CCCs. One CCC (center west side) has a PLL. The AGL015 and AGL030 do not have a PLL

The six CCC blocks are located at the four corners and the centers of the east and west sides. One CCC (center west side) has a PLL.

All six CCC blocks are usable; the four corner CCCs and the east CCC allow simple clock delay operations as well as clock spine access.

The inputs of the six CCC blocks are accessible from the FPGA core or from one of several inputs located near the CCC that have dedicated connections to the CCC block.

The CCC block has these key features:

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## Guidelines

## Toggle Rate Definition

A toggle rate defines the frequency of a net or logic element relative to a clock. It is a percentage. If the toggle rate of a net is 100%, this means that this net switches at half the clock frequency. Below are some examples:

- The average toggle rate of a shift register is 100% because all flip-flop outputs toggle at half of the clock frequency.
- The average toggle rate of an 8-bit counter is 25%:

```
- Bit 0 (LSB) = 100%

- Bit 1 = 50%

- Bit 2 = 25%
```

- Bit 7 (MSB) = 0.78125%
- Average toggle rate = (100% + 50% + 25% + 12.5% + ... + 0.78125%) / 8

### **Enable Rate Definition**

Output enable rate is the average percentage of time during which tristate outputs are enabled. When nontristate output buffers are used, the enable rate should be 100%.

Table 2-23 • Toggle Rate Guidelines Recommended for Power Calculation

Component	Definition	Guideline
$\alpha_1$	Toggle rate of VersaTile outputs	10%
$\alpha_2$	I/O buffer toggle rate	10%

Table 2-24 • Enable Rate Guidelines Recommended for Power Calculation

Component	Definition	Guideline
$\beta_1$	I/O output buffer enable rate	100%
$\beta_2$	RAM enable rate for read operations	12.5%
$\beta_3$	RAM enable rate for write operations	12.5%

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### **Timing Characteristics**

Applies to 1.5 V DC Core Voltage

Table 2-51 • 3.3 V LVTTL / 3.3 V LVCMOS Low Slew – Applies to 1.5 V DC Core Voltage

Commercial-Case Conditions: T<sub>J</sub> = 70°C, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 3.0 V

Applicable to Advanced I/O Banks

Drive Strength	Speed Grade	t <sub>DOUT</sub>	t <sub>DP</sub>	t <sub>DIN</sub>	t <sub>PY</sub>	t <sub>EOUT</sub>	t <sub>ZL</sub>	t <sub>ZH</sub>	t <sub>LZ</sub>	t <sub>HZ</sub>	t <sub>ZLS</sub>	t <sub>ZHS</sub>	Units
2 mA	Std.	0.97	4.47	0.18	0.85	0.66	4.56	3.89	2.24	2.19	8.15	7.48	ns
4 mA	Std.	0.97	4.47	0.18	0.85	0.66	4.56	3.89	2.24	2.19	8.15	7.48	ns
6 mA	Std.	0.97	3.74	0.18	0.85	0.66	3.82	3.37	2.49	2.63	7.42	6.96	ns
8 mA	Std.	0.97	3.74	0.18	0.85	0.66	3.82	3.37	2.49	2.63	7.42	6.96	ns
12 mA	Std.	0.97	3.23	0.18	0.85	0.66	3.30	2.98	2.66	2.91	6.89	6.57	ns
16 mA	Std.	0.97	3.08	0.18	0.85	0.66	3.14	2.89	2.70	2.99	6.74	6.48	ns
24 mA	Std.	0.97	3.00	0.18	0.85	0.66	3.06	2.91	2.74	3.27	6.66	6.50	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

Table 2-52 • 3.3 V LVTTL / 3.3 V LVCMOS High Slew – Applies to 1.5 V DC Core Voltage Commercial-Case Conditions: T<sub>J</sub> = 70°C, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 3.0 V Applicable to Advanced I/O Banks

Drive Strength	Speed Grade	t <sub>DOUT</sub>	t <sub>DP</sub>	t <sub>DIN</sub>	t <sub>PY</sub>	t <sub>EOUT</sub>	t <sub>ZL</sub>	t <sub>ZH</sub>	t <sub>LZ</sub>	t <sub>HZ</sub>	t <sub>ZLS</sub>	t <sub>ZHS</sub>	Units
2 mA	Std.	0.97	2.73	0.18	0.85	0.66	2.79	2.22	2.25	2.32	6.38	5.82	ns
4 mA	Std.	0.97	2.73	0.18	0.85	0.66	2.79	2.22	2.25	2.32	6.38	5.82	ns
6 mA	Std.	0.97	2.32	0.18	0.85	0.66	2.37	1.85	2.50	2.76	5.96	5.45	ns
8 mA	Std.	0.97	2.32	0.18	0.85	0.66	2.37	1.85	2.50	2.76	5.96	5.45	ns
12 mA	Std.	0.97	2.09	0.18	0.85	0.66	2.14	1.68	2.67	3.05	5.73	5.27	ns
16 mA	Std.	0.97	2.05	0.18	0.85	0.66	2.10	1.64	2.70	3.12	5.69	5.24	ns
24 mA	Std.	0.97	2.07	0.18	0.85	0.66	2.12	1.60	2.75	3.41	5.71	5.20	ns

#### Notes:

- 1. Software default selection highlighted in gray.
- 2. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

Table 2-53 • 3.3 V LVTTL / 3.3 V LVCMOS Low Slew – Applies to 1.5 V DC Core Voltage

Commercial-Case Conditions: T<sub>J</sub> = 70°C, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 3.0 V

Applicable to Standard Plus Banks

Drive Strength	Speed Grade	t <sub>DOUT</sub>	t <sub>DP</sub>	t <sub>DIN</sub>	t <sub>PY</sub>	t <sub>EOUT</sub>	t <sub>ZL</sub>	t <sub>ZH</sub>	t <sub>LZ</sub>	t <sub>HZ</sub>	t <sub>ZLS</sub>	t <sub>ZHS</sub>	Units
2 mA	Std.	0.97	3.94	0.18	0.85	0.66	4.02	3.46	1.98	2.03	7.62	7.05	ns
4 mA	Std.	0.97	3.94	0.18	0.85	0.66	4.02	3.46	1.98	2.03	7.62	7.05	ns
6 mA	Std.	0.97	3.24	0.18	0.85	0.66	3.31	2.99	2.21	2.42	6.90	6.59	ns
8 mA	Std.	0.97	3.24	0.18	0.85	0.66	3.31	2.99	2.21	2.42	6.90	6.59	ns
12 mA	Std.	0.97	2.76	0.18	0.85	0.66	2.82	2.63	2.36	2.68	6.42	6.22	ns
16 mA	Std.	0.97	2.76	0.18	0.85	0.66	2.82	2.63	2.36	2.68	6.42	6.22	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

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Table 2-92 • 2.5 V LVCMOS High Slew – Applies to 1.2 V DC Core Voltage

Commercial-Case Conditions: T<sub>J</sub> = 70°C, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 2.3 V

Applicable to Standard Plus Banks

Drive Strength	Speed Grade	t <sub>DOUT</sub>	t <sub>DP</sub>	t <sub>DIN</sub>	t <sub>PY</sub>	t <sub>EOUT</sub>	t <sub>ZL</sub>	t <sub>ZH</sub>	t <sub>LZ</sub>	t <sub>HZ</sub>	t <sub>ZLS</sub>	t <sub>ZHS</sub>	Units
2 mA	Std.	1.55	2.91	0.26	1.19	1.10	2.95	2.66	2.50	2.72	8.74	8.45	ns
4 mA	Std.	1.55	2.91	0.26	1.19	1.10	2.95	2.66	2.50	2.72	8.74	8.45	ns
6 mA	Std.	1.55	2.51	0.26	1.19	1.10	2.54	2.18	2.75	3.21	8.33	7.97	ns
8 mA	Std.	1.55	2.51	0.26	1.19	1.10	2.54	2.18	2.75	3.21	8.33	7.97	ns
12 mA	Std.	1.55	2.29	0.26	1.19	1.10	2.32	1.94	2.94	3.52	8.10	7.73	ns

#### Notes:

- 1. Software default selection highlighted in gray.
- 2. For specific junction temperature and voltage supply levels, refer to Table 2-7 on page 2-7 for derating values.

Table 2-93 • 2.5 V LVCMOS Low Slew – Applies to 1.2 V DC Core Voltage

Commercial-Case Conditions: T<sub>J</sub> = 70°C, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 2.3 V

Applicable to Standard Banks

Drive Strength	Speed Grade	t <sub>DOUT</sub>	t <sub>DP</sub>	t <sub>DIN</sub>	t <sub>PY</sub>	t <sub>EOUT</sub>	t <sub>ZL</sub>	t <sub>ZH</sub>	t <sub>LZ</sub>	t <sub>HZ</sub>	Units
2 mA	Std.	1.55	4.85	0.26	1.15	1.10	4.93	4.55	2.13	2.24	ns
4 mA	Std.	1.55	4.85	0.26	1.15	1.10	4.93	4.55	2.13	2.24	ns
6 mA	Std.	1.55	4.09	0.26	1.15	1.10	4.16	3.95	2.38	2.71	ns
8 mA	Std.	1.55	4.09	0.26	1.15	1.10	4.16	3.95	2.38	2.71	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-7 on page 2-7 for derating values.

Table 2-94 • 2.5 V LVCMOS High Slew – Applies to 1.2 V DC Core Voltage

Commercial-Case Conditions: T<sub>J</sub> = 70°C, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 2.3 V

Applicable to Standard Banks

Drive Strength	Speed Grade	t <sub>DOUT</sub>	t <sub>DP</sub>	t <sub>DIN</sub>	t <sub>PY</sub>	t <sub>EOUT</sub>	t <sub>ZL</sub>	t <sub>ZH</sub>	t <sub>LZ</sub>	t <sub>HZ</sub>	Units
2 mA	Std.	1.55	2.76	0.26	1.15	1.10	2.80	2.52	2.13	2.32	ns
4 mA	Std.	1.55	2.76	0.26	1.15	1.10	2.80	2.52	2.13	2.32	ns
6 mA	Std.	1.55	2.39	0.26	1.15	1.10	2.42	2.05	2.38	2.80	ns
8 mA	Std.	1.55	2.39	0.26	1.15	1.10	2.42	2.05	2.38	2.80	ns

#### Notes:

- 1. Software default selection highlighted in gray.
- 2. For specific junction temperature and voltage supply levels, refer to Table 2-7 on page 2-7 for derating values.

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## 1.8 V LVCMOS

Low-voltage CMOS for 1.8 V is an extension of the LVCMOS standard (JESD8-5) used for general-purpose 1.8 V applications. It uses a 1.8 V input buffer and a push-pull output buffer.

Table 2-95 • Minimum and Maximum DC Input and Output Levels
Applicable to Advanced I/O Banks

1.8 V LVCMOS		VIL	VIH		VOL	VOH	IOL	ЮН	IOSH	IOSL	IIL <sup>1</sup>	IIH <sup>2</sup>
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA <sup>3</sup>	Max. mA <sup>3</sup>	μ <b>Α</b> <sup>4</sup>	μ <b>Α</b> <sup>4</sup>
2 mA	-0.3	0.35 * VCCI	0.65 * VCCI	1.9	0.45	VCCI - 0.45	2	2	9	11	10	10
4 mA	-0.3	0.35 * VCCI	0.65 * VCCI	1.9	0.45	VCCI - 0.45	4	4	17	22	10	10
6 mA	-0.3	0.35 * VCCI	0.65 * VCCI	1.9	0.45	VCCI - 0.45	6	6	35	44	10	10
8 mA	-0.3	0.35 * VCCI	0.65 * VCCI	1.9	0.45	VCCI - 0.45	8	8	45	51	10	10
12 mA	-0.3	0.35 * VCCI	0.65 * VCCI	1.9	0.45	VCCI - 0.45	12	12	91	74	10	10
16 mA	-0.3	0.35 * VCCI	0.65 * VCCI	1.9	0.45	VCCI - 0.45	16	16	91	74	10	10

#### Notes:

- 1. IIL is the input leakage current per I/O pin over recommended operation conditions where -0.3 V < VIN < VIL.
- 2. IIH is the input leakage current per I/O pin over recommended operating conditions VIH < VIN < VCCI. Input current is larger when operating outside recommended ranges
- 3. Currents are measured at 100°C junction temperature and maximum voltage.
- 4. Currents are measured at 85°C junction temperature.
- 5. Software default selection highlighted in gray.

Table 2-96 • Minimum and Maximum DC Input and Output Levels
Applicable to Standard Plus I/O Banks

1.8 V LVCMOS	VIL		VIH		VOL	VOH		ЮН	IOSH	IOSL	IIL <sup>1</sup>	IIH <sup>2</sup>
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mΑ	mA	Max. mA <sup>3</sup>	Max. mA <sup>3</sup>	μ <b>Α</b> <sup>4</sup>	μA <sup>4</sup>
2 mA	-0.3	0.35 * VCCI	0.65 * VCCI	1.9	0.45	VCCI - 0.45	2	2	9	11	10	10
4 mA	-0.3	0.35 * VCCI	0.65 * VCCI	1.9	0.45	VCCI - 0.45	4	4	17	22	10	10
6 mA	-0.3	0.35 * VCCI	0.65 * VCCI	1.9	0.45	VCCI - 0.45	6	6	35	44	10	10
8 mA	-0.3	0.35 * VCCI	0.65 * VCCI	1.9	0.45	VCCI - 0.45	8	8	35	44	10	10

### Notes:

- 1. IIL is the input leakage current per I/O pin over recommended operation conditions where -0.3 V < VIN < VIL.
- 2. IIH is the input leakage current per I/O pin over recommended operating conditions VIH < VIN < VCCI. Input current is larger when operating outside recommended ranges
- 3. Currents are measured at 100°C junction temperature and maximum voltage.
- 4. Currents are measured at 85°C junction temperature.
- 5. Software default selection highlighted in gray.

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Table 2-138 • Minimum and Maximum DC Input and Output Levels for LVCMOS 1.2 V Wide Range Applicable to Standard Plus I/O Banks

1.2 V LVCI Wide Ran		VIL VIH		VOL	VOH	IOL	ЮН	IOSL	IOSH	IIL <sup>2</sup>	IIH <sup>3</sup>		
Drive Strength	Equivalent Software Default Drive Strength Option <sup>1</sup>	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA <sup>4</sup>	Max. mA <sup>4</sup>	μ <b>Α</b> <sup>5</sup>	μΑ <sup>5</sup>
100 μΑ	2mA	-0.3	0.35 * VCCI	0.65 * VCCI	1.26	0.25 * VCCI	0.75 * VCCI	100	100	20	26	10	10

#### Notes:

- The minimum drive strength for the default LVCMOS 1.2 V software configuration when run in wide range is ± 100 μA. The drive strength displayed in software is supported in normal range only. For a detailed I/V curve, refer to the IBIS models.
- 2. IIL is the input leakage current per I/O pin over recommended operation conditions where -0.3 V < VIN < VIL.
- 3. IIH is the input leakage current per I/O pin over recommended operating conditions VIH < VIN < VCCI. Input current is larger when operating outside recommended ranges
- 4. Currents are measured at 100°C junction temperature and maximum voltage.
- 5. Currents are measured at 85°C junction temperature.
- 6. Software default selection highlighted in gray.

Table 2-139 • Minimum and Maximum DC Input and Output Levels for LVCMOS 1.2 V Wide Range Applicable to Standard I/O Banks

1.2 V LVCI Wide Rang			VIL	VIH		VOL	VOH	IOL	ЮН	IOSL	IOSH	IIL <sup>2</sup>	IIH <sup>3</sup>
Drive Strength	Equivalent Software Default Drive Strength Option <sup>1</sup>	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA <sup>4</sup>	Max. mA <sup>4</sup>	μ <b>Α</b> <sup>5</sup>	μ <b>Α</b> <sup>5</sup>
100 μΑ	1 mA	-0.3	0.35 * VCCI	0.65 * VCCI	3.6	0.25 * VCCI	0.75 * VCCI	100	100	20	26	10	10

#### Notes:

- The minimum drive strength for the default LVCMOS 1.2 V software configuration when run in wide range is ± 100 μA. The drive strength displayed in software is supported in normal range only. For a detailed I/V curve, refer to the IBIS models.
- 2. IIL is the input leakage current per I/O pin over recommended operation conditions where -0.3 V < VIN < VIL.
- 3. IIH is the input leakage current per I/O pin over recommended operating conditions VIH < VIN < VCCI. Input current is larger when operating outside recommended ranges
- 4. Currents are measured at 100°C junction temperature and maximum voltage.
- 5. Currents are measured at 85°C junction temperature.
- 6. Software default selection highlighted in gray.

Table 2-140 • 1.2 V LVCMOS Wide Range AC Waveforms, Measuring Points, and Capacitive Loads

Input Low (V)	Input High (V)	Measuring Point* (V)	C <sub>LOAD</sub> (pF)
0	1.2	0.6	5

Note: \*Measuring point = Vtrip. See Table 2-29 on page 2-28 for a complete table of trip points.

### Timing Characteristics

Refer to LVCMOS 1.2 V (normal range) "Timing Characteristics" on page 2-75 for worst-case timing.

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## **Output Enable Register**

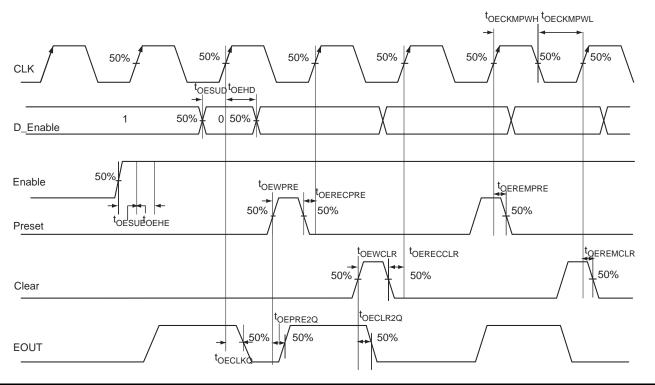


Figure 2-20 • Output Enable Register Timing Diagram

## **Timing Characteristics**

1.5 V DC Core Voltage

Table 2-161 • Output Enable Register Propagation Delays

Commercial-Case Conditions: T<sub>J</sub> = 70°C, Worst-Case VCC = 1.425 V

Parameter	Description	Std.	Units
t <sub>OECLKQ</sub>	Clock-to-Q of the Output Enable Register	0.75	ns
t <sub>OESUD</sub>	SUD Data Setup Time for the Output Enable Register		ns
t <sub>OEHD</sub>	Data Hold Time for the Output Enable Register	0.00	ns
t <sub>OESUE</sub>	Enable Setup Time for the Output Enable Register	0.73	ns
t <sub>OEHE</sub>	Enable Hold Time for the Output Enable Register	0.00	ns
t <sub>OECLR2Q</sub>	Asynchronous Clear-to-Q of the Output Enable Register	1.13	ns
t <sub>OEPRE2Q</sub>	Asynchronous Preset-to-Q of the Output Enable Register	1.13	ns
toeremclr	Asynchronous Clear Removal Time for the Output Enable Register	0.00	ns
toerecclr	Asynchronous Clear Recovery Time for the Output Enable Register	0.24	ns
t <sub>OEREMPRE</sub>	Asynchronous Preset Removal Time for the Output Enable Register	0.00	ns
t <sub>OERECPRE</sub>	Asynchronous Preset Recovery Time for the Output Enable Register	0.24	ns
t <sub>OEWCLR</sub>	Asynchronous Clear Minimum Pulse Width for the Output Enable Register	0.19	ns
t <sub>OEWPRE</sub>	Asynchronous Preset Minimum Pulse Width for the Output Enable Register	0.19	ns
t <sub>OECKMPWH</sub>	Clock Minimum Pulse Width High for the Output Enable Register	0.31	ns
t <sub>OECKMPWL</sub>	Clock Minimum Pulse Width Low for the Output Enable Register	0.28	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

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Table 2-179 • AGL600 Global Resource

Commercial-Case Conditions: T<sub>J</sub> = 70°C, VCC = 1.425 V

			Std.	
Parameter	Description	Min. <sup>1</sup>	Max. <sup>2</sup>	Units
t <sub>RCKL</sub>	Input Low Delay for Global Clock	1.48	1.82	ns
t <sub>RCKH</sub>	Input High Delay for Global Clock	1.52	1.94	ns
t <sub>RCKMPWH</sub>	Minimum Pulse Width High for Global Clock	1.18		ns
t <sub>RCKMPWL</sub>	Minimum Pulse Width Low for Global Clock	1.15		ns
t <sub>RCKSW</sub>	Maximum Skew for Global Clock		0.42	ns

#### Notes:

- Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element, located in a lightly loaded row (single element is connected to the global net).
- 2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element, located in a fully loaded row (all available flip-flops are connected to the global net in the row).
- 3. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

Table 2-180 • AGL1000 Global Resource

Commercial-Case Conditions: T<sub>J</sub> = 70°C, VCC = 1.425 V

			Std.		
Parameter	Description	Ī	Min. <sup>1</sup>	Max. <sup>2</sup>	Units
t <sub>RCKL</sub>	Input Low Delay for Global Clock		1.55	1.89	ns
t <sub>RCKH</sub>	Input High Delay for Global Clock		1.60	2.02	ns
t <sub>RCKMPWH</sub>	Minimum Pulse Width High for Global Clock		1.18		ns
t <sub>RCKMPWL</sub>	Minimum Pulse Width Low for Global Clock		1.15		ns
t <sub>RCKSW</sub>	Maximum Skew for Global Clock			0.42	ns

#### Notes:

- 1. Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element, located in a lightly loaded row (single element is connected to the global net).
- 2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element, located in a fully loaded row (all available flip-flops are connected to the global net in the row).
- 3. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

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	CS196	CS196		
Pin Number	AGL125 Function	Pin Number	AGL125 Function	
A1	GND	C9	IO23RSB0	
A2	GAA0/IO00RSB0	C10	IO29RSB0	
А3	GAC0/IO04RSB0	C11	VCCIB0	
A4	GAC1/IO05RSB0	C12	IO42RSB0	
A5	IO09RSB0	C13	GNDQ	
A6	IO15RSB0	C14	IO44RSB0	
A7	IO18RSB0	D1	IO127RSB1	
A8	IO22RSB0	D2	IO129RSB1	
A9	IO27RSB0	D3	GAA2/IO132RSB1	
A10	GBC0/IO35RSB0	D4	IO126RSB1	
A11	GBB0/IO37RSB0	D5	IO06RSB0	
A12	GBB1/IO38RSB0	D6	IO13RSB0	
A13	GBA1/IO40RSB0	D7	IO19RSB0	
A14	GND	D8	IO21RSB0	
B1	VCCIB1	D9	IO26RSB0	
B2	VMV0	D10	IO31RSB0	
В3	GAA1/IO01RSB0	D11	IO30RSB0	
B4	GAB1/IO03RSB0	D12	VMV0	
B5	GND	D13	IO46RSB0	
В6	IO16RSB0	D14	GBC2/IO45RSB0	
В7	IO20RSB0	E1	IO125RSB1	
B8	IO24RSB0	E2	GND	
B9	IO28RSB0	E3	IO131RSB1	
B10	GND	E4	VCCIB1	
B11	GBC1/IO36RSB0	E5	NC	
B12	GBA0/IO39RSB0	E6	IO08RSB0	
B13	GBA2/IO41RSB0	E7	IO17RSB0	
B14	GBB2/IO43RSB0	E8	IO12RSB0	
C1	GAC2/IO128RSB1	E9	IO11RSB0	
C2	GAB2/IO130RSB1	E10	NC	
C3	GNDQ	E11	VCCIB0	
C4	VCCIB0	E12	IO32RSB0	
C5	GAB0/IO02RSB0	E13	GND	
C6	IO14RSB0	E14	IO34RSB0	
C7	VCCIB0	F1	IO124RSB1	
C8	NC	F2	IO114RSB1	

	CS196
Pin Number	AGL125 Function
F3	IO113RSB1
F4	IO112RSB1
F5	IO111RSB1
F6	NC
F7	VCC
F8	VCC
F9	NC
F10	IO07RSB0
F11	IO25RSB0
F12	IO10RSB0
F13	IO33RSB0
F14	IO47RSB0
G1	GFB1/IO121RSB1
G2	GFA0/IO119RSB1
G3	GFA2/IO117RSB1
G4	VCOMPLF
G5	GFC0/IO122RSB1
G6	VCC
<b>G</b> 7	GND
G8	GND
G9	VCC
G10	GCC0/IO52RSB0
G11	GCB1/IO53RSB0
G12	GCA0/IO56RSB0
G13	IO48RSB0
G14	GCC2/IO59RSB0
H1	GFB0/IO120RSB1
H2	GFA1/IO118RSB1
H3	VCCPLF
H4	GFB2/IO116RSB1
H5	GFC1/IO123RSB1
H6	VCC
H7	GND
H8	GND
H9	VCC
H10	GCC1/IO51RSB0

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	QN132
Pin Number	AGL125 Function
A1	GAB2/IO69RSB1
A2	IO130RSB1
A3	VCCIB1
A4	GFC1/IO126RSB1
A5	GFB0/IO123RSB1
A6	VCCPLF
A7	GFA1/IO121RSB1
A8	GFC2/IO118RSB1
A9	IO115RSB1
A10	VCC
A11	GEB1/IO110RSB1
A12	GEA0/IO107RSB1
A13	GEC2/IO104RSB1
A14	IO100RSB1
A15	VCC
A16	IO99RSB1
A17	IO96RSB1
A18	IO94RSB1
A19	IO91RSB1
A20	IO85RSB1
A21	IO79RSB1
A22	VCC
A23	GDB2/IO71RSB1
A24	TDI
A25	TRST
A26	GDC1/IO61RSB0
A27	VCC
A28	IO60RSB0
A29	GCC2/IO59RSB0
A30	GCA2/IO57RSB0
A31	GCA0/IO56RSB0
A32	GCB1/IO53RSB0
A33	IO49RSB0
A34	VCC
A35	IO44RSB0
A36	GBA2/IO41RSB0

QN132			
Pin Number	AGL125 Function		
A37	GBB1/IO38RSB0		
A38	GBC0/IO35RSB0		
A39	VCCIB0		
A40	IO28RSB0		
A41	IO22RSB0		
A42	IO18RSB0		
A43	IO14RSB0		
A44	IO11RSB0		
A45	IO07RSB0		
A46	VCC		
A47	GAC1/IO05RSB0		
A48	GAB0/IO02RSB0		
B1	IO68RSB1		
B2	GAC2/IO131RSB1		
В3	GND		
B4	GFC0/IO125RSB1		
B5	VCOMPLF		
В6	GND		
B7	GFB2/IO119RSB1		
B8	IO116RSB1		
B9	GND		
B10	GEB0/IO109RSB1		
B11	VMV1		
B12	FF/GEB2/IO105RSB1		
B13	IO101RSB1		
B14	GND		
B15	IO98RSB1		
B16	IO95RSB1		
B17	GND		
B18	IO87RSB1		
B19	IO81RSB1		
B20	GND		
B21	GNDQ		
B22	TMS		
B23	TDO		
B24	GDC0/IO62RSB0		

QN132			
Pin Number	AGL125 Function		
B25	GND		
B26	NC		
B27	GCB2/IO58RSB0		
B28	GND		
B29	GCB0/IO54RSB0		
B30	GCC1/IO51RSB0		
B31	GND		
B32	GBB2/IO43RSB0		
B33	VMV0		
B34	GBA0/IO39RSB0		
B35	GBC1/IO36RSB0		
B36	GND		
B37	IO26RSB0		
B38	IO21RSB0		
B39	GND		
B40	IO13RSB0		
B41	IO08RSB0		
B42	GND		
B43	GAC0/IO04RSB0		
B44	GNDQ		
C1	GAA2/IO67RSB1		
C2	IO132RSB1		
C3	VCC		
C4	GFB1/IO124RSB1		
C5	GFA0/IO122RSB1		
C6	GFA2/IO120RSB1		
C7	IO117RSB1		
C8	VCCIB1		
C9	GEA1/IO108RSB1		
C10	GNDQ		
C11	GEA2/IO106RSB1		
C12	IO103RSB1		
C13	VCCIB1		
C14	IO97RSB1		
C15	IO93RSB1		
C16	IO89RSB1		

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VQ100			
Pin Number	AGL250 Function		
1	GND		
2	GAA2/IO118UDB3		
3	IO118VDB3		
4	GAB2/IO117UDB3		
5	IO117VDB3		
6	GAC2/IO116UDB3		
7	IO116VDB3		
8	IO112PSB3		
9	GND		
10	GFB1/IO109PDB3		
11	GFB0/IO109NDB3		
12	VCOMPLF		
13	GFA0/IO108NPB3		
14	VCCPLF		
15	GFA1/IO108PPB3		
16	GFA2/IO107PSB3		
17	VCC		
18	VCCIB3		
19	GFC2/IO105PSB3		
20	GEC1/IO100PDB3		
21	GEC0/IO100NDB3		
22	GEA1/IO98PDB3		
23	GEA0/IO98NDB3		
24	VMV3		
25	GNDQ		
26	GEA2/IO97RSB2		
27	FF/GEB2/IO96RSB2		
28	GEC2/IO95RSB2		
29	IO93RSB2		
30	IO92RSB2		
31	IO91RSB2		
32	IO90RSB2		
33	IO88RSB2		
34	IO86RSB2		
35	IO85RSB2		
36	IO84RSB2		

VQ100			
Pin Number	AGL250 Function		
37	VCC		
38	GND		
	-		
39	VCCIB2		
40	IO77RSB2		
41	IO74RSB2		
42	IO71RSB2		
43	GDC2/IO63RSB2		
44	GDB2/IO62RSB2		
45	GDA2/IO61RSB2		
46	GNDQ		
47	TCK		
48	TDI		
49	TMS		
50	VMV2		
51	GND		
52	VPUMP		
53	NC		
54	TDO		
55	TRST		
56	VJTAG		
57	GDA1/IO60USB1		
58	GDC0/IO58VDB1		
59	GDC1/IO58UDB1		
60	IO52NDB1		
61	GCB2/IO52PDB1		
62	GCA1/IO50PDB1		
63	GCA0/IO50NDB1		
64	GCC0/IO48NDB1		
65	GCC1/IO48PDB1		
66	VCCIB1		
67	GND		
68	VCC		
69	IO43NDB1		
70	GBC2/IO43PDB1		
71	GBB2/IO42PSB1		
72	IO41NDB1		

VQ100	
Pin Number	AGL250 Function
73	GBA2/IO41PDB1
74	VMV1
75	GNDQ
76	GBA1/IO40RSB0
77	GBA0/IO39RSB0
78	GBB1/IO38RSB0
79	GBB0/IO37RSB0
80	GBC1/IO36RSB0
81	GBC0/IO35RSB0
82	IO29RSB0
83	IO27RSB0
84	IO25RSB0
85	IO23RSB0
86	IO21RSB0
87	VCCIB0
88	GND
89	VCC
90	IO15RSB0
91	IO13RSB0
92	IO11RSB0
93	GAC1/IO05RSB0
94	GAC0/IO04RSB0
95	GAB1/IO03RSB0
96	GAB0/IO02RSB0
97	GAA1/IO01RSB0
98	GAA0/IO00RSB0
99	GNDQ
100	VMV0



FG144	
Pin Number	AGL400 Function
K1	GEB0/IO136NDB3
K2	GEA1/IO135PDB3
K3	GEA0/IO135NDB3
K4	GEA2/IO134RSB2
K5	IO127RSB2
K6	IO121RSB2
K7	GND
K8	IO104RSB2
K9	GDC2/IO82RSB2
K10	GND
K11	GDA0/IO79VDB1
K12	GDB0/IO78VDB1
L1	GND
L2	VMV3
L3	FF/GEB2/IO133RSB2
L4	IO128RSB2
L5	VCCIB2
L6	IO119RSB2
L7	IO114RSB2
L8	IO110RSB2
L9	TMS
L10	VJTAG
L11	VMV2
L12	TRST
M1	GNDQ
M2	GEC2/IO132RSB2
M3	IO129RSB2
M4	IO126RSB2
M5	IO124RSB2
M6	IO122RSB2
M7	IO117RSB2
M8	IO115RSB2
M9	TDI
M10	VCCIB2
M11	VPUMP
M12	GNDQ

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FG144	
Pin Number	AGL600 Function
K1	GEB0/IO145NDB3
K2	GEA1/IO144PDB3
K3	GEA0/IO144NDB3
K4	GEA2/IO143RSB2
K5	IO119RSB2
K6	IO111RSB2
K7	GND
K8	IO94RSB2
K9	GDC2/IO91RSB2
K10	GND
K11	GDA0/IO88NDB1
K12	GDB0/IO87NDB1
L1	GND
L2	VMV3
L3	FF/GEB2/IO142RSB2
L4	IO136RSB2
L5	VCCIB2
L6	IO115RSB2
L7	IO103RSB2
L8	IO97RSB2
L9	TMS
L10	VJTAG
L11	VMV2
L12	TRST
M1	GNDQ
M2	GEC2/IO141RSB2
M3	IO138RSB2
M4	IO123RSB2
M5	IO126RSB2
M6	IO134RSB2
M7	IO108RSB2
M8	IO99RSB2
M9	TDI
M10	VCCIB2
M11	VPUMP
M12	GNDQ

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FG144		
Pin Number	AGL1000 Function	
K1	GEB0/IO189NDB3	
K2	GEA1/IO188PDB3	
K3	GEA0/IO188NDB3	
K4	GEA2/IO187RSB2	
K5	IO169RSB2	
K6	IO152RSB2	
K7	GND	
K8	IO117RSB2	
K9	GDC2/IO116RSB2	
K10	GND	
K11	GDA0/IO113NDB1	
K12	GDB0/IO112NDB1	
L1	GND	
L2	VMV3	
L3	FF/GEB2/IO186RSB2	
L4	IO172RSB2	
L5	VCCIB2	
L6	IO153RSB2	
L7	IO144RSB2	
L8	IO140RSB2	
L9	TMS	
L10	VJTAG	
L11	VMV2	
L12	TRST	
M1	GNDQ	
M2	GEC2/IO185RSB2	
M3	IO173RSB2	
M4	IO168RSB2	
M5	IO161RSB2	
M6	IO156RSB2	
M7	IO145RSB2	
M8	IO141RSB2	
M9	TDI	
M10	VCCIB2	
M11	VPUMP	
M12	GNDQ	
IVI I Z	GINDQ	

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	FG256
Pin Number	AGL400 Function
R5	IO123RSB2
R6	IO118RSB2
R7	IO112RSB2
R8	IO106RSB2
R9	IO100RSB2
R10	IO96RSB2
R11	IO89RSB2
R12	IO85RSB2
R13	GDB2/IO81RSB2
R14	TDI
R15	NC
R16	TDO
T1	GND
T2	IO126RSB2
T3	FF/GEB2/IO133RSB2
T4	IO124RSB2
T5	IO116RSB2
T6	IO113RSB2
T7	IO107RSB2
T8	IO105RSB2
Т9	IO102RSB2
T10	IO97RSB2
T11	IO92RSB2
T12	GDC2/IO82RSB2
T13	IO86RSB2
T14	GDA2/IO80RSB2
T15	TMS
T16	GND

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	FG256	
Pin Number	AGL1000 Function	
R5	IO168RSB2	
R6	IO163RSB2	
R7	IO157RSB2	
R8	IO149RSB2	
R9	IO143RSB2	
R10	IO138RSB2	
R11	IO131RSB2	
R12	IO125RSB2	
R13	GDB2/IO115RSB2	
R14	TDI	
R15	GNDQ	
R16	TDO	
T1	GND	
T2	IO183RSB2	
Т3	FF/GEB2/IO186RSB2	
T4	IO172RSB2	
T5	IO170RSB2	
T6	IO164RSB2	
T7	IO158RSB2	
Т8	IO153RSB2	
Т9	IO142RSB2	
T10	IO135RSB2	
T11	IO130RSB2	
T12	GDC2/IO116RSB2	
T13	IO120RSB2	
T14	GDA2/IO114RSB2	
T15	TMS	
T16	GND	

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	FG484
Pin Number   AGL1000 Functio	
B7	IO15RSB0
B8	IO19RSB0
B9	IO24RSB0
B10	IO31RSB0
B11	IO39RSB0
B12	IO48RSB0
B13	IO54RSB0
B14	IO58RSB0
B15	IO63RSB0
B16	IO66RSB0
B17	IO68RSB0
B18	IO70RSB0
B19	NC
B20	NC
B21	VCCIB1
B22	GND
C1	VCCIB3
C2	IO220PDB3
C3	NC
C4 NC	NC
C5	GND
C6	IO10RSB0
C7	IO14RSB0
C8	VCC
C9	VCC
C10	IO30RSB0
C11	IO37RSB0
C12	IO43RSB0
C13	NC
C14	VCC
C15	VCC
C16	NC
C17	NC
C18	GND
C19	NC
C20	NC

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## Datasheet Information

Revision / Version	Changes	Page
Advance v0.7 (continued)	The former Table 2-16 • Maximum I/O Frequency for Single-Ended and Differential I/Os in All Banks in IGLOO Devices (maximum drive strength and high slew selected) was removed.	
	The "During Flash*Freeze Mode" section was updated to include information about the output of the I/O to the FPGA core.	2-57
	Table 2-31 • Flash*Freeze Pin Location in IGLOO Family Packages (device-independent) was updated to add UC81 and CS281. Flash*Freeze pins were assigned for CS81, CS121, and CS196.	2-61
	Figure 2-40 • Flash*Freeze Mode Type 2 - Timing Diagram was updated to modify the LSICC Signal.	2-55
	Information regarding calculation of the quiescent supply current was added to the "Quiescent Supply Current" section.	3-6
	Table 3-8 • Quiescent Supply Current (I <sub>DD</sub> ) Characteristics, IGLOO Flash*Freeze Mode <sup>†</sup> was updated.	3-6
	Table 3-9 • Quiescent Supply Current ( $I_{DD}$ ) Characteristics, IGLOO Sleep Mode (VCC = 0 V) <sup>†</sup> was updated.	3-6
	Table 3-11 • Quiescent Supply Current (I <sub>DD</sub> ), No IGLOO Flash*Freeze Mode1 was updated.	3-7
	Table 3-115 • Minimum and Maximum DC Input and Output Levels was updated.	3-58
	Table 3-156 • JTAG 1532 was updated and Table 3-155 • JTAG 1532 is new.	3-104
	The "121-Pin CSP" and "281-Pin CSP" packages are new.	4-5, 4-7
	The "81-Pin CSP" table for the AGL030 device was updated to change the G6 pin function to IO44RSB1 and the JG pin function to IO45RSB1.	4-4
	The "121-Pin CSP" table for the AGL060 device is new.	4-6
	The "256-Pin FBGA" table for the AGL1000 device is new.	4-34
	The "281-Pin CSP" table for the AGL 600 device is new.	4-8
	The "100-Pin VQFP" table for the AGL060 device is new.	4-18
	The "144-Pin FBGA" table for the AGL250 device is new.	4-24
	The "144-Pin FBGA" table for the AGL1000 device is new.	4-28
	The "484-Pin FBGA" table for the AGL600 device is new.	4-38
	The "484-Pin FBGA" table for the AGL1000 device is new.	4-43
Advance v0.6 (November 2007) Table 1 • IGLOO Product Family, the "I/Os Per Package1" table, and the Ordering Information", and the Temperature Grade Offerings table were to add the UC81 package.		i, ii, iii, iv
	The "81-Pin µCSP" table for the AGL030 device is new.	4-3
	The "81-Pin CSP" table for the AGL030 device is new.	4-1
Advance v0.5 (September 2007)	Table 1 • IGLOO Product Family was updated for AGL030 in the Package Pins section to change CS181 to CS81.	i

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